## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

James W. Blatchford, Jr., et al.

Serial No.

Unknown

Filing Date:

July 8, 2003

Title:

GENERATING AN OPTICAL MODEL FOR LENS

ABERRATIONS

## **Mail Stop Patent Application**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

## **INFORMATION DISCLOSURE STATEMENT**

Applicants respectfully request, pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, that the references listed on the attached PTO-1449 form be considered and cited in the examination of the above-identified patent application. Copies of these references are enclosed for the convenience of the Examiner. No representation is made that a search has been made, that these references qualify as prior art or that these references are material to the patentability of the present application.

Respectfully submitted,

Baker Botts L.L.P. Attorneys for Applicant

Keiko Ichiye

Reg. No. 45,460

Date:

2003

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	Information Disclosure Citation In an Application			Docket Number TI-35516 (032350.B504)	Unknown J		Filing Date July 8, 2003	
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